

Case U.S. 170  
10/059321  
01/31/02

U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10059321	01/31/2002	438	424.000	2812	ISAAC, S

APPLICANTS: Chuan Lin;

\*\*CONTINUING DATA VERIFIED:

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\*\*FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		ATTORNEY DOCKET NO
35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		2001 P 14585 US
Identified and Acknowledged Examiners's initials <i>Haroldt Kane SDF</i>		
TITLE: Reduction of negative bias temperature instability in narrow width PMOS using F2 implantation		

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
Assistant Examiner		Total Claims	Print Claim for O.G.
Primary Examiner		DRAWING	
PREPARED FOR ISSUE		Sheets Drwg.	Figs. Drwg. Print Fig.
Application Examiner		WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.	

ISSUE FEE	
Amount Due	Date Paid

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